

## 8. Literatura

- [Alam54] M. N. Alam, M. Blackman, D. W. Pashley, *High-angle Kikuchi Patterns*, Proceedings of Royal Society, vol. 222 pp. 224-242, 1954.
- [Archi04] W. Archibald, *Microstructural Characterization of Aluminum Thin Films and Foils: Grain Boundary Topology, Properties and Statistics*, Phd Thesis, Carnegie Mellon University, 2004.
- [Asto89] J. Astola, P. Haavisto, Y. Neuvo, *Detail Preserving Monochrome and Color Image Enhancement Algorithms*, J. C. Simon (Ed.), Elsevier, Amsterdam, 1989.
- [Babus02] R. Babuska, U. Kaymak, P. J. van der Veen, *Improved Covariance Estimation for GustafsonKessel Clustering*, In best Proceedings of 2002 IEEE International Conference on Fuzzy Systems, pp. 1081-1085, Honolulu, Hawaii, May 2002.
- [Bakh99] A. Bakhtazad, A. Palazoglu, J. A. Romagnoli, *Process Data De-noising Using Wavelet Transform*, Intelligent Data Analysis, vol. 3, p. 267-285, 1999.
- [Ball81] D. H. Ballard, *Generalizing the Hough Transform to Detect Duplicate Arbitrary Shapes*, Pattern Recognition, vol. 13, no. 2, pp. 111-122, 1981.
- [Basc02] J. Bascou, A. Tommasi, D. Mainprice, *Plastic Deformation and Development of Similar Clinopyroxene Lattice Preferred Orientations in Eclogites*, Journal of Structural Geology, 24, pp. 1357-1368, 2002.
- [Bent90] D. Ben-Tzvi, M. B. Sandler, *A Combinatorial Hough Transform*, Pattern Recognition Letters, vol. 11, no. 3, pp. 167-174, 1990.
- [Berg91] J. R. Bergen, H. Shvaytser, *A Probabilistic Algorithm for Computing Hough Transforms*, Journal of Algorithms, vol. 12., no. 4, pp. 639-656, 1991.
- [Bezd81] J. C. Bezdek, *Pattern Recognition with Fuzzy Objective Function Algorithms*, Plenum Press, 1981.
- [Blas1] B. Balasko, J. Abonyi, B. Feil, *Fuzzy Clustering and Data Analysis Toolbox*, <http://www.fmt.vein.hu/softcomp/>,
- [Brew02] L. N. Brewer, *Misorientation Mapping for Visualization of Plastic Strain via Electron Back-Scattered Diffraction*, Microscopy & Microanalysis, 2002.
- [Brow84] D. R. K. Brownrigg, *The Weighted Median Filter*, Communications of the ACM, vol. 27, Issue 8, pp. 807-818, 1984.
- [Bung00] H. J. Bunge, *Industrial Applications of X-ray diffraction*, New York-Basel, pp. 919, 2000.
- [Burg98] C. J. C. Burges, *A Tutorial on Support Vector Machines for Pattern Recognition*, Data Mining and Knowledge Discovery, vol. 2, pp. 121-167, 1998.
- [Burr98] C. S. Burrus, R. A. Gopinath, H. Guo, *Introduction to wavelets and wavelet transforms*, Saddle pper River, NJ (USA): Prentice Hall, 1998.
- [Cabu04] C. Cabus, H. Regle, B. Bacroix, *Phases Transformation Textures in Steels Filozofia*, International Conference on Advanced High Strength Sheet Steels for Automotive Applications, Winter Park, Colorado, USA, 2004.
- [Cand98] E. J. Candès, *Ridgelets: Theory and Applications*, Ph.D. thesis, Department of Statistics, Stanford University, 1998.
- [Chan00a] S. G. Chang, M. Vetterli, B. Yu, *Adaptive Wavelet Thresholding for Image Denoising and Compression*, IEEE Transactions on Image Processing, vol. 9(9), pp. 1532-1546,

Sep. 2000.

- [Chan00b] T. Chan, A. Marquina, P. Mulet, *High-order Total Variation-based Image Restoration*, SIAM Journal on Scientific Computing, vol. 22, no. 2, pp. 503-516, 2000.
- [Chen04] G. Y. Chen, T. D. Bui, A. Krzyzak, *Image Denoising Using Neighbouring Wavelet Coefficients*, IEEE International Conference on Acoustics, Speech and Signal Processing, vol. 2, pp. 917-920, 2004.
- [Chen94] W. Chen, M. C. Chaturvedi, *The Influence of Grain Boundary Properties on Creep Fracture*, Superalloys, vol. 718, 1994.
- [Choi98] H. Choi, R. G. Baraniuk, *Analysis of Wavelet Domain Wiener Filters*, IEEE International Symposium on Time-Frequency and Time-Scale Analysis, (Pittsburgh), Oct.1998.
- [Cris00] N. Cristianini, J. Shawe-Taylor, *An Introduction to Support Vector Machines and Other Kernel-based Learning Methods*, Cambridge University Press, ISBN 0-521-78019-5, 2000.
- [Dark03] C. Dark, S. Speller, H. Wu, A. J. Wilkinson and C. R. M. Grovenor, *Grain Boundary Properties of Tl-2212 Thin Films*, Proceedings of European Conference on Applied Superconductivity, Sorrento 2003.
- [Daub92] I. Daubechies, *Ten Lectures on Wavelets*, CBMS-NSF Regional Conference Series in Applied Mathematics, Society for Industrial & Applied Math, 1992.
- [Dixo06] S. Dixon, S. Essex, *Texture Measurement of Aluminum Sheet Using Electron Backscattered Diffraction and Electromagnetic Acoustic Transducers*, The 45th Annual British Conference on NDT, Stratford, 2006.
- [Do03] M. N. Do, M. Vetterli, *The Finite Ridgelet Transform for Image Representation*, IEEE Transactions on Image Processing, vol. 12, pp. 16-28, Jan. 2003.
- [Dono94] D. L. Donoho, I. M. Johnstone, *Ideal Spatial Adaptation by Wavelet Shrinkage*, Biometrika, vol. 81(3), pp. 425-455, Aug. 1994.
- [Dono95a] D. L. Donoho, *De-noising by Soft Thresholding*, IEEE Transactions on Information Theory, vol. 41(3), pp. 613-627, May 1995.
- [Dono95b] D. L. Donoho, I. M. Johnstone, *Adapting to Smoothness via Wavelet Shrinkage*, Journal of the Statistical Association, vol. 90(432), pp. 1200-1224, Dec. 1995.
- [Drie05] I. V. Driessche, B. Schoofs, G. Penneman, E. Bruneel, S. Hoste, *Review of the Application of High Temperature Superconductors in Coated Conductor Development and the Measurement of Their Properties*, Measurement science review, vol. 5, Section 3, 2005.
- [Driv96] J. H. Driver, M. C. Theyssier, C. Maurice, *Electron Backscattered Diffraction Microtexture Studies on Hot Deformed Aluminium Crystals*, Material Science Technology, vol. 12, pp. 851-858, 1996.
- [Duda72] R. O. Duda, P. E. Hart, *Use of the Hough Transformation to Detect Lines and Curves in Pictures*, Communications ACM, vol. 15, pp. 11-15, 1972.
- [Ecab04] O. Ecabert, J. P. Thiran, *Adaptive Hough Transform for the Detection of Natural Shapes under Weak Affine Transformations*, Pattern Recognition Letters, vol. 25, pp. 1411-1419, 2004.
- [Fitt98] N. C. Fitton, S. J. D. Cox, *Optimizing the Application of the Hough Transform for Automatic Feature Extraction from Geoscientific Images*, Computers and Geosciences, vol. 24, no. 10, pp. 933-951, 1998.
- [Floer02] W. Floer, Y. M. Hu, U. Krupp, H. J. Christ, *Application of the EBSD Technique to Study the Initiation and Propagation of Short Cracks*, Practical Metallography, vol. 7, 2002.
- [Frac04a] R. Frączek, T. Zieliński, *Praktyczne aspekty nowego algorytmu detekcji linii*

*Kikuchiego*, Materiały XIV Sympozjum „Modelowanie i Symulacja Systemów Pomiarowych, Krynica Górska 2004.

- [Frac04b] R. Frączek, T. Zieliński, *Algorytm detekcji linii Kikuchiego w mikroskopii elektronowej*, Kongres Metrologii, Wrocław 2004.
- [Frac05a] R. Frączek, T. Zieliński, *Algorytm detekcji linii Kikuchiego z użyciem zmodyfikowanej transformacji Hougha*, XV Sympozjum „Modelowanie i Symulacja Systemów Pomiarowych”, str. 209-218, Krynica Górska 2005.
- [Frac05b] R. Frączek, T. Zieliński, *New Algorithm for Kikuchi Lines Detection in Electron Microscopy Images*, European Signal Processing Conference EUSIPCO-2005, Antalya, 2005.
- [Frac06a] R. Frączek, *Ulepszony algorytm detekcji linii Kikuchiego*, XVI Sympozjum „Modelowanie i Symulacja Systemów Pomiarowych”, Krynica 2006.
- [Frac06b] R. Frączek, T. Zieliński, *Peak Detection Methods in Hough-Transform Based Kikuchi Bands Extraction*, International Conference of Signals and Electronic Systems ICSES-206, Łódź 2006.
- [Frac06c] R. Frączek, T. Zieliński, *Application of Advanced Image Processing Techniques to Automatic Kikuchi Lines Detection*, European Signal Processing Conference EUSIPCO-2006, Florencja 2006.
- [Free91] W. T. Freeman, E. H. Adelson, *The Design and Use of Steerable Filters*, IEEE Trans. Pattern Analysis and Machine Intelligence, vol. 13, no. 9, pp. 891-906, 1991.
- [Fund03] J. J. Funderberger, A. Morawiec, E. Bouzy, J. S. Lecomte, *Polycrystal Orientation Maps from TEM*, Ultramicroscopy, vol. 96, pp. 127-137, 2003.
- [Gala99] C. Galambos, J. Matas, J. Kittler, *Progressive Probabilistic Hough Transform for Line Detection*, IEEE Computer Society Conference on Computer Vision and Pattern Recognition, vol. 1, p.1554, 1999.
- [Gey02] N. Gey, E. Gautier, M. Humbert, A. Cerqueira, J.L. Bechade, P. Archambault, *Study of the  $\alpha/\alpha'$  Phase Transformation of Zy-4 in Presence of Applied Stresses at Heating: Analysis of the Inherited Microstructures and Textures*, Journal of Nuclear Materials, vol. 302, pp.175-184, 2002.
- [Gilb04] G. Gilboa, N. Sochen, Y. Y. Zeevi, *Image Enhancement and Denoising by Complex Diffusion Processes*, IEEE Trans. On Pattern Analysis and Machine Intelligence, vol. 26, no. 8, Aug. 2004.
- [Gonz93] R. C. Gonzalez, R. E. Woods, *Digital Image Processing*, Prentice Hall, 1993.
- [Gopi97] D. Gopikrishna, S. N. Jha, L. N. Dash, *Influence of Microstructure on Fatigue Properties of Alloy 718*, The Fourth International Special Emphasis Symposium on Superalloy, Pittsburgh, Pennsylvania, 1997.
- [Groe81] T. M. van Veen, F. C. A. Groen, *Discretization Errors in the Hough Transform*, Pattern Recognition, vol. 14, no. 1, 1981.
- [Gunn98] S. Gunn, *Support Vector Machines for Classification and Regression*, Technical Report ISIS-1-98, Department of Electronics and Computer Science, University of Southampton, 1998.
- [Hans97] K. Hansen, J. D. Andersen, *Understanding the Hough Transform: Hough Cell Support and its Utilization*, Image and vision computing, vol. 15, no. 3, pp. 205-218, 1997.
- [Hanz99] A. B. Hamza, P. L. Luque-Escamilla, J. M. Aroza, R. R. Roldan, *Removing Noise and Preserving Details with Relaxed Median Filters*, Journal of Mathematical Imaging and Vision, vol. 11, pp. 161-177, 1999.
- [Heid00] F. Heidelbach, K. Kunze, H. R. Wenk, *Texture Analysis of a Recrystallized Quartzite Using Electron Diffraction in the Scanning Electron Microscope*, Journal Of Structural Geology, vol. 22, pp. 91-104, 2000.

- [Houg62] P. V. C. Hough, *Method and Means for Recognizing Complex Patterns*, U. S. Patent 3,069,654, 1962.
- [Hump01] F. J. Humphreys, *Grain and Subgrain Characterisation by Electron Backscatter Diffraction*, *Journal of Material Science*, vol. 36, pp. 3833-3854, 2001.
- [Hump99] F. J. Humphreys, *Quantitative Metallography by Electron Backscattered Diffraction*, *Journal of Microscopy*, vol. 195, pp.170-185, 1999.
- [Hunt02] A. Hunter, M. Ferry, *Comparative Study of Texture Development in Strip-cast Ferritic and Austenitic Stainless Steels*, *Scripta Materialia*, Sep. 2002.
- [Hurl03] P. J. Hurley, F. J. Humphreys, *The Application of EBSD to the Study of Substructural Development in a Cold Rolled Single-phase Aluminium Alloy*, *Acta Materialia*, Feb. 2003.
- [Ill87] J. Illingworth, J. Kittler, *The Adaptive Hough Transform*, *IEEE Transactions on Pattern Analysis and Machine Intelligence*, vol. 9, no. 5, pp. 690-698, 1987.
- [Ill88] J. Illingworth, J. Kittler, *A Survey of the Hough Transform*, *CVGIP*, vol. 44, pp. 87-116, 1988.
- [Inte1] Internetowy podręcznik statystyki, <http://www.statsoft.pl/textbook/stathome.html>
- [Jaco04] M. Jacob, M. Unser, *Design of Steerable Filters for Feature Detection Using Canny-Like Criteria*, *IEEE Transactions on Pattern Analysis and Machine Intelligence*, vol. 26, no. 8, Aug. 2004.
- [Jain89] A. K. Jain, *Fundamentals of Digital Image Processing*, Prentice-Hall International, ISBN 0-13-332578-4, 1989.
- [Jans01] M. Jansen, *Noise Reduction by Wavelet Thresholding*, vol. 161. Springer Verlag, United States of America, 1st edition, 2001.
- [Jans99] M. Jansen, G. Uytterhoeven, A. Bultheel, *De-noising by Integer Wavelet Transforms and Generalized Cross Validation*, *Medical Physics*, vol. 26, pp. 622-630, 1999.
- [Joun1] P. H. Joneau, *Introduction to EBSD*, <http://cime.epfl.ch>
- [Käl94] H. Kälviäinen, P. Hirvonen, E. Oja, L. Xu, *Comparisons of Probabilistic and Non-probabilistic Hough Transforms*, *Proceedings of the 3rd European Conference on Computer Vision*, pp. 351-360, 1994.
- [Kesi00] A. L. Kesidis, N. Papamarkos, *On the Gray-scale Inverse Hough transform*, *Image and Vision Computing*, vol. 18, pp. 607-618, 2000.
- [Kimm75] C. Kimme, D. H. Ballard, J. Sklansky, *Finding Circles by an Array of Accumulators*, *Communications of the Association for Computing Machinery*, vol. 18, pp. 120-122, 1975.
- [Kiry91] N. Kiryati, Y. Eldar, A. M. Bruckstein, *A Probabilistic Hough Transform*, *Pattern Recognition*, vol. 24, no. 4., pp. 303-316, 1991.
- [Koon76] L. G. Koontz, W. P. M. Narendra, K. A. Fukunaga, *Graph-Theoretic Approach to Nonparametric Cluster Analysis*, *IEEE Transactions on Computers*, no. 9, pp. 936-944, 1976.
- [Lam92] L. Lam, S-W. Lee, C. Y. Wuen, *Thinning Methodologies – A Comprehensive Survey*, *IEEE Transactions on PAMI*, vol. 14, no. 9, pp. 869-885, 1992.
- [Lass98] K. Lasse, *Automatic High-precision Measurements of the Location and Width of Kikuchi Bands in Electron Backscatter Diffraction Patterns*, *Journal of Microscopy*, vol.190, pt.3, pp.375-391, 1998.
- [Leav92] V. F. Leavers, *Shape Detection in Computer Vision Using the Hough Transform*, Springer-Verlag, 1992.
- [Leav93] V. F. Leavers, *Which Hough transform?*, *Image Understanding*, vol. 58, no. 2, pp. 250-264, 1993.
- [Lim90] J. S. Lim, *Two-Dimensional Signal and Image Processing*, Englewood Cliffs, NJ, Prentice Hall, pp. 536-540, 1990.

- [Lo95] Rong-Chin Lo, Wen-Hsiang Tsai, *Gray-scale Hough Transform for Thick Line Detection in Gray-scale Images*, Pattern Recognition, vol. 28, no. 5, pp. 647-661, 1995.
- [Lysa03] M. Lysaker, A. Lundervold, X. C. Tai, *Noise Removal Using Fourth-Order Partial Differential Equation With Applications to Medical Magnetic Resonance Images in Space and Time*, IEEE Transactions on Image Processing, vol. 12, no. 12, pp. 1579-1590, 2003.
- [Mali02] W. Malina, S. Ablameyko, W. Pawlak, *Podstawy cyfrowego przetwarzania obrazów*, Akademicka Oficyna Wydawnicza Exit, Warszawa 2002.
- [Mall99] S. G. Mallat, *A Wavelet Tour of Signal Processing*, Elsevier, ISBN: 012466606X, 1999.
- [Mari91] A. Marion, *An Introduction to Image Processing*, Chapman and Hall, p. 274, 1991.
- [Math1] Mathworks, [www.mathworks.com](http://www.mathworks.com)
- [Mirp04] K. Mirpuri, H. Wendrock, et al., *High Temperature Behavior of Cu Films Studied in-situ by Electron Backscatter Diffraction*, European Workshop on Materials for Advanced Metallization, Brussels, Belgium, Elsevier, 2004.
- [Mora02] A. Morawiec, J. J. Funderberger, E. Bouzy and J. S. Lecomte, *EP – A Program for Determination of Crystallite Orientations from TEM Kikuchi and CBED Diffraction Patterns*, Journal of Applied Crystallography, vol. 35, pp. 287, 2002.
- [Motw04] M. Motwani, M. Gadiya, R. Motwani, *A Survey of Image Denoising Techniques*, in Proceedings of GSPx, 2004.
- [Naka97] S. Nakamura, G. Fasol, S. J. Pearton, *The Blue Laser Diode*, Springer, Berlin, p. 23, 1997.
- [Naso96] G. P. Nason, *Wavelet Shrinkage by Cross-validation*, Journal of Royal Statistics Society, vol. 58, pp. 463-479, 1996.
- [Oie1] Oxford Instruments Electron Backscatter Diffraction site, [www.ebsd.com](http://www.ebsd.com)
- [Osow94] S. Osowski, *Sieci neuronowe*, Oficyna Wydawnicza Politechniki Warszawskiej, Warszawa 1994.
- [Otho02] M. A Othon, *Electron Back-Scattered Diffraction Misorientation Mapping Applied to Stress Corrosion Cracking of Stainless Steels*, Microscopy & Microanalysis, 2002.
- [Piaz04] S. Piazolo, M. W. Jessell, D. J. Priori, P. D. Bons, *The Integration of Experimental in-situ EBSD Observations and Numerical Simulations: a Novel Technique of Microstructural Process Analysis*, Journal of Microscopy, vol. 213, pp. 273-284, 2004.
- [Piaz04] S. Piazolo, G. Steward, N. Seaton, D. J. Priori, *Recrystallization and Phase Transformation in Polycrystalline Materials: New Insights in Processes Using Combined in-situ Heating Experiments and Detailed EBSD Analysis*, Materials Science Forum, pp. 1407-1412, 2004.
- [Piaz05] S. Piazolo, D. J. Priori, M. D. Holness, *The Use of Combined Cathodoluminescence and EBSD Analysis: A Case Study Investigating Grain Boundary Migration Mechanisms in Quartz*, Journal of Microscopy, vol. 217, pp. 152-161, 2005.
- [Pita01] I. Pitas, *Digital Image Processing Algorithms and Applications*, John Wiley & Sons; 1 edition, ISBN: 0471377392, 2001.
- [Plat00] K. N. Plataniotis, A. N. Venetsanopoulos, *Color Image Processing and Applications*, Berlin, Springer, 2000.
- [Poli1] Politechnika Śląska, Katedra Podstaw Konstrukcji Maszyn <https://kpk.m.polsl.pl/>
- [Port01] J. Portilla, V. Strela, M. J. Wainwright, E. P. Simoncelli, *Adaptive Wiener denoising Using a Gaussian Scale Mixture Model in the Wavelet Domain*, Proceedings of the 8th International Conference on Image Processing, Thessaloniki, Greece, 2001.
- [Prin92] J. Princen, J. Illingworth, J. Kittler, *A Formal Definition of the Hough Transform:*

*Properties and Relationships*, Journal of Mathematical Imaging and Vision, vol. 1, 1992.

- [Prio99] D. Prior, A. Boyle, F. Brenker, M. Cheadle, A. Day, G. Lopez, L. Peruzzo, G. Potts, S. Reddy, R. Spiess, N. Timms, P. Trimby, J. Wheeler, L. Zetterström, *The Application of Electron Backscatter Diffraction and Orientation Contrast Imaging in the SEM to Textural Problems in Rocks*, American Mineralogist, vol. 84, pp. 1741-1759, 1999.
- [Prio99] D. J. Prior, J. Wheeler, *Feldspar fabrics in a Greenschist Facies Albite-rich Mylonite from Electron Backscatter Diffraction*, Tectonophysics, vol. 303, pp. 29-49, 1999.
- [Rand00] V. Randle, O. Engler, *Introduction to Texture Analysis Macrotecture, Microtexture and Orientation Mapping*, ISBN 90-5699-224-4, Harwood Academic, Feb. 2000.
- [Rand92] V. Randle, *Microtexture Determination and Its Applications*, Institute of Materials, 1992.
- [Ratl81] P. A. Ratley, A. G. Lundgren, *Sampling the 2-D Radon Transformation*, IEEE Acoustic Speech Signal Processing, vol. 29(5), 1981.
- [Riss89] T. Risse, *Hough Transform for Line Recognition*, Computer Vision and Image Processing, vol. 46, pp. 327-345, 1989.
- [Roscl] <http://pawelroszczak.republika.pl/mlp/mlp.html#classification>
- [Rudi92] L. I. Rudin, S. Osher, E. Fatemi, *Nonlinear Total Variation Based Noise Removal Algorithms*, Physica D, vol. 60, pp. 259-268, 1992.
- [Sahh97] P. Sahho, C. Wilkins, J. Yeager, *Threshold Selection Using Renyi's Entropy*, Pattern Recognition, vol. 30, pp. 71-84, 1997.
- [Schu04] J. W. Schultze, B. Davepon, F. Karman, C. Rosenkranz, A. Schreiber, O. Voigt, *Corrosion and Passivation in Nanoscopic and Microscopic Dimensions: the Influence of Grains and Grain Boundaries*, Corrosion Engineering, Science and Technology, vol. 39, no. 1, pp. 45-52, 2004.
- [Schw00] A. J. Schwarz, M. Kumar, B. L. Adams, *Electron Backscatter Diffraction in Materials Science*, ISBN 0-306-46487-X, Kluwer Academic/Plenum Publishers, 2000.
- [Schw98] R. A. Schwarzer, *Crystallography and Microstructure of Thin Films Studied by X-ray and Electron Diffraction*, Materials Science Forum, vol. 287-288, pp. 23-60, 1998.
- [Skar93] W. Skarbek, *Metody reprezentacji obrazów cyfrowych*, Akademicka Oficyna Wydawnicza PLJ, Warszawa, 1993.
- [Star02] J. L. Starck, J. L. SE. Candès, D. L. Donoho, *Curvelet Transform for Image Denoising*, IEEE Transactions on Image Processing, vol. 11, no. 6, pp. 670-684, 2002.
- [Star03] J. L. Starck, F. Murtagh, E. Candès, D. L. Donoho, *Gray and Color Image Contrast Enhancement by the Curvelet Transform*, IEEE Transactions on Image Processing, vol. 12, no. 6, pp. 706-717, 2003.
- [Star94] J. L. Starck, A. Bijaoui, *Filtering and Deconvolution by the Wavelet Transform*, Signal Processing, vol. 35, pp. 195-211, 1994.
- [Star99] J. L. Starck, F. Murtagh, *Multiscale Entropy Filtering*, Signal Processing, vol. 76, pp. 147-165, 1999.
- [Stre00] V. Strela, *Denoising via Block Wiener filtering in Wavelet Domain*, in 3rd European Congress of Mathematics, Barcelona, Jul. 2000.
- [Szab90] J. Szabatin, *Podstawy teorii sygnałów*, Wydawnictwa Komunikacji i Łączności, Warszawa, 1990.
- [Sztw06a] K. Sztwiertnia, M. Bieda, G. Sawina, *Determination of Crystallite Orientations Using TEM. Examples of Measurements*, Archives of Metallurgy, vol. 51, no. 1, pp. 55-62, 2006.

- [Sztw06b] K. Sztwiertnia, M. Faryna, G. Sawina, *Misorientation Characteristics of Interphase Boundaries in Particulate Al<sub>2</sub>O<sub>3</sub>-based Composites*, Journal of the European Ceramic Society, vol. 26, pp. 2973-2978, 2006.
- [Tade93] R. Tadeusiewicz, *Sieci neuronowe*, Akademicka Oficyna Wydawnicza RM., Warszawa 1993.
- [Toft96] P. Toft, *The Radon Transform – Theory and Implementation*, Ph. D. Thesis, Department of Mathematical Modeling, Technical University of Denmark, 1996.
- [Trag02] C. Trager-Cowan, F. Sweeney, J. Hastie, S. K. Manson-Smith, D. A. Cowan, C. T. Foxon, I. Harrison, S. D. Hersee, D. McColl, A. Mohammed, S. V. Novikov, K. P. O'Donnell, D. Zubia, *Characterization of Nitride Thin Films by Electron Backscatter Diffraction*, Journal of Microscopy, vol. 205, pp. 226-230, Mar. 2002.
- [Trim00] P. W. Trimby, M. R. Drury, C. J. Spiers, *Recognizing the Crystallographic Signature of Recrystallisation Processes in Deformed Rocks: a Study of Experimentally Deformed Rocksalt*, Journal of Structural Geology, vol. 22, pp.1609-1620, 2000.
- [Vand02] L. Vandeveld, J. Melkebeek, *Modeling of Magnetoelastic Material*, IEEE Transactions on Magnetics, vol. 38, no. 2, pp. 993-996, 2002.
- [Vena73] J. A. Venables, C. J. Harland, *Electron Back-Scattering Patterns – A New Technique for Obtaining Crystallographic Information in the Scanning Electron Microscope*, Philosophical Magazine vol. 27, pp. 1193-1200, 1973.
- [Wiki1] Encyklopedia internetowa, <http://pl.wikipedia.org/>
- [Wrig91] S. I. Wright, B. L. Adams, *Automated Lattice Orientation Determination from Electron Backscatter Kikuchi Diffraction Patterns*, Mobbing Textures & Microstructures, vol. 14-18, pp. 273-278, 1991.
- [Yang95] R. Yang, L. Yin, M. Gabouj, Y. Neuvo, *Optimal Weighted Median Filtering under Structural Constraints*, IEEE Trans. Signal Processing, vol. 43, pp. 591-603, 1995.
- [Yip92] R. K. K. Yip, P. K. S. Tam, D. N. K. Leung, *Modification of the Hough Transform for Circles and Ellipses Detection Using a 2-dimensional Array*, Pattern Recognition, vol. 25, pp. 1007-1022, 1992.
- [You00] Yu-Li You, M. Kaveh, *Fourth Order Partial Differential Equations for Noise Removal*, IEEE Transactions on Image Processing, vol. 9, no. 10, pp. 1723-1730, Oct. 2000.
- [Yuan03] Y. Yuan, A. J. Davenport, M. Strangwood, R. Ambat, *The Effect of Crystallographic Misorientation on Intergranular Corrosion of Aluminum Alloy 5182*, 44th Corrosion Science Symposium, Electrochem 2003, Southampton, UK, Sep. 2003.
- [Yuen89] H. K. Yuen, J. Illingworth, J. Kittler, *Detecting Partially Occluded Ellipses Using the Hough Transform*, Image and Vision Computing, vol. 7, pp. 31-37, 1989.
- [Ziel02] T. P. Zieliński, *Od teorii do cyfrowego przetwarzania sygnałów*, Wydział EAIiE AGH, Kraków, 2002.
- [Ziel05] T. P. Zieliński, *Cyfrowe przetwarzanie sygnałów – od teorii do zastosowań*, Wydawnictwa Komunikacji i Łączności, Warszawa, 2005.